

# Field Stop Trench IGBT With Soft Fast Recovery Diode and V<sub>CESAT</sub>, V<sub>TH</sub> Binning

# 650 V, 160 A

# AFGY160T65SPD-B4

# **Features**

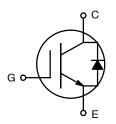
- AEC-Q101 Qualified and PPAP Capable
- Very Low Saturation Voltage:  $V_{CE(sat)} = 1.6 \text{ V (Typ.)}$  @  $I_C = 160 \text{ A}$
- Maximum Junction Temperature:  $T_I = 175$ °C
- Positive Temperature Co-Efficient
- Tight Parameter Distribution
- High Input Impedance
- 100% of the Parts are Dynamically Tested
- Short Circuit Ruggedness > 6 μs @ 25°C
- Copacked with Soft, Fast Recovery Extremefast Diode
- This Device is Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

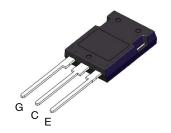
#### **Benefits**

- Very Low Conduction and Switching Losses for a High Efficiency Operation in Various Applications
- Rugged Transient Reliability
- Outstanding Parallel Operation Performance with Balance Current Sharing
- Low EMI

# **Applications**

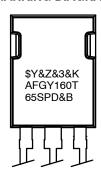
- Traction Inverter for HEV/EV
- Auxiliary DC/AC Converter
- Motor Drives
- Other Power-Train Applications Requiring High Power Switch





**TO-247-3LD CASE 340CU** 

#### **MARKING DIAGRAM**



= <b>onsemi</b> Logo
= Assembly Plant Code
= Date Code (Year & Week)
= Lot Traceability Code
= Specific Device Code
= BIN Designator

#### ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

# **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Ratings	Unit
V <sub>CES</sub>	Collector to Emitter Voltage	650	V
$V_{GES}$	Gate to Emitter Voltage	±20	V
	Transient Gate to Emitter Voltage	±30	V
I <sub>C</sub>	Collector Current @ T <sub>C</sub> = 25°C (Note 1)	240	А
	Collector Current @ T <sub>C</sub> = 100°C	220	А
I <sub>Nominal</sub>	Nominal Current	160	А
I <sub>CM</sub>	Pulsed Collector Current	480	А
I <sub>FM</sub>	Diode Forward Current @ T <sub>C</sub> = 25°C (Note 1)	240	Α
	Diode Forward Current @ T <sub>C</sub> = 100°C	188	А
$P_{D}$	Maximum Power Dissipation @ T <sub>C</sub> = 25°C	882	W
	Maximum Power Dissipation @ T <sub>C</sub> = 100°C	441	W
SCWT	Short Circuit Withstand Time @ T <sub>C</sub> = 25°C	6	μs
ΔV/Δt	Voltage Transient Ruggedness (Note 2)	10	V/ns
TJ	Operating Junction Temperature	-55 to +175	°C
T <sub>stg</sub>	Storage Temperature Range	-55 to +175	°C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# THERMAL CHARACTERISTICS

Symbol	Parameter	Тур.	Max.	Units
R <sub>θJC</sub> (IGBT)	Thermal Resistance, Junction to Case	-	0.17	°C/W
R <sub>θJC</sub> (Diode)	Thermal Resistance, Junction to Case	-	0.32	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient	-	40	°C/W

# PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Bin Designator	Packing Type	Qty per Tube/Reel*
AFGY160T65SPDA	AFGY160T65SPD-B4	Α	Tube	30
AFGY160T65SPDB	AFGY160T65SPD-B4	В	Tube	30
AFGY160T65SPDC	AFGY160T65SPD-B4	С	Tube	30
AFGY160T65SPDD	AFGY160T65SPD-B4	D	Tube	30

<sup>\*</sup>Generally all tubes in one box will belong to the same bin. In rare and unusual cases there may be tubes from more than one bin inside one box. Such mixing would not be considered a quality excursion.



<sup>1.</sup> Limited to bondwire.

<sup>2.</sup>  $V_{CC}$  = 400 V,  $V_{GE}$  = 15 V,  $I_{CE}$  = 480 A, Inductive load.

The primary container quantity (MPQ) for these binning products is 30 units and therefore partial box shipment can be expected.

# **ELECTRICAL CHARACTERISTICS OF THE IGBT** ( $T_J = 25$ °C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARAC	TERISTICS					
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	$V_{GE} = 0 \text{ V}, I_{C} = 1 \text{ mA}$	650	-	-	V
$\Delta BV_CES / \Delta T_J$	Temperature Coefficient of Breakdown Voltage	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	-	0.6	-	V/°C
I <sub>CES</sub>	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0 V$	_	-	40	μΑ
I <sub>GES</sub>	G-E Leakage Current	V <sub>GE</sub> = V <sub>GES</sub> , V <sub>CE</sub> = 0 V	-	-	±250	nA
ON CHARACT	ERISTICS			-		
V <sub>GE(th)A</sub>	G-E Threshold (Bin A)	Ic = 160 mA; V <sub>CE</sub> = V <sub>GE</sub>	5.15	5.5	6.3	V
V <sub>CE(sat)A</sub>	Collector to Emitter Saturation Voltage (Bin A)	Ic = 160 A; V <sub>GE</sub> = 15 V	1.5	1.6	1.67	V
V <sub>GE(th)B</sub>	G-E Threshold (Bin B)	Ic = 160 mA; V <sub>CE</sub> = V <sub>GE</sub>	5.15	5.5	6.3	V
V <sub>CE(sat)B</sub>	Collector to Emitter Saturation Voltage (Bin B)	Ic = 160 A; V <sub>GE</sub> = 15 V	1.57	1.64	2.05	V
V <sub>GE(th)C</sub>	G-E Threshold (Bin C)	Ic = 160 mA; V <sub>CE</sub> = V <sub>GE</sub>	4.3	5.3	5.65	V
V <sub>CE(sat)C</sub>	Collector to Emitter Saturation Voltage (Bin C)	Ic = 160 A; V <sub>GE</sub> = 15 V	1.5	1.6	1.67	V
V <sub>GE(th)D</sub>	G-E Threshold (Bin D)	Ic = 160 mA; V <sub>CE</sub> = V <sub>GE</sub>	4.3	5.3	5.65	V
V <sub>CE(sat)D</sub>	Collector to Emitter Saturation Voltage (Bin D)	Ic = 160 A; V <sub>GE</sub> = 15 V	1.57	1.64	2.05	V
V <sub>GE(th)</sub>	G-E Threshold	Ic = 160 mA; V <sub>CE</sub> = V <sub>GE</sub>	4.3	5.3	6.3	V
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage	Ic = 160 A; V <sub>GE</sub> = 15 V	_	1.6	2.05	V
, ,	Ic = 160 A; V <sub>GE</sub> = 15 V; T <sub>J</sub> = 175°C		-	2.15	-	V
DYNAMIC CH	ARACTERISTICS			•		
C <sub>ies</sub>	Input Capacitance	$V_{CE} = 30 \text{ V}, V_{GE} = 0 \text{ V},$	_	6710	-	pF
C <sub>oes</sub>	Output Capacitance	f = 1 MHz	_	450	-	pF
C <sub>res</sub>	Reverse Transfer Capacitance	_	_	55	-	pF
R <sub>G</sub>	Internal Gate Resistance	f = 1 MHz	_	3	_	Ω
SWITCHING C	CHARACTERISTICS			1	<u>I</u>	
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 400 V, I <sub>C</sub> = 160 A,	_	53	_	ns
T <sub>r</sub>	Rise Time	$R_G = 5 \Omega$ , $V_{GE} = 15 V$ , Inductive Load, $T_J = 25^{\circ}C$	_	197	_	ns
T <sub>d(off)</sub>	Turn-Off Delay Time		_	98	_	ns
T <sub>f</sub>	Fall Time	_	_	141	_	ns
E <sub>on</sub>	Turn-On Switching Loss		_	12.4	_	mJ
E <sub>off</sub>	Turn-Off Switching Loss		_	5.7	_	mJ
E <sub>ts</sub>	Total Switching Loss		_	18.1	_	mJ
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 400 V, I <sub>C</sub> = 160 A,	_	52	_	ns
T <sub>r</sub>	Rise Time	$R_G = 5 \Omega$ , $V_{GE} = 15 V$ , Inductive Load, $T_J = 175^{\circ}C$	_	236	_	ns
T <sub>d(off)</sub>	Turn-Off Delay Time		_	104	_	ns
T <sub>f</sub>	Fall Time	†	_	204	_	ns
E <sub>on</sub>	Turn-On Switching Loss	-	_	21	_	mJ
E <sub>off</sub>	Turn-Off Switching Loss	-	_	8.5	_	mJ
E <sub>ts</sub>	Total Switching Loss	_	_	29.5	_	mJ



# **ELECTRICAL CHARACTERISTICS OF THE IGBT** (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
SWITCHING CHARACTERISTICS						
Qg	Total Gate Charge	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 160 A, V <sub>GE</sub> = 15 V	-	163	245	nC
Q <sub>ge</sub>	Gate to Emitter Charge	V <sub>GE</sub> = 15 V	-	50	_	nC
Q <sub>gc</sub>	Gate to Collector Charge		-	49	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

# ELECTRICAL CHARACTERISTICS OF THE DIODE (T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
$V_{FM}$	Diode Forward Voltage	I <sub>F</sub> = 160 A	T <sub>J</sub> = 25°C	-	1.4	1.7	V
			T <sub>J</sub> = 175°C	-	1.35	-	
E <sub>rec</sub>	Reverse Recovery Energy	$V_{CE} = 400 \text{ V, I}_{F} = 160 \text{ A,}$ $\Delta I_{F}/\Delta t = 1000 \text{ A/}\mu\text{s}$	$T_J = 25^{\circ}C$	-	598	-	μJ
			T <sub>J</sub> = 175°C	-	4000	-	
T <sub>rr</sub>	Diode Reverse Recovery		$T_J = 25^{\circ}C$	-	132	-	ns
	Time		T <sub>J</sub> = 175°C	-	245	-	
Q <sub>rr</sub>	Diode Reverse Recovery		T <sub>J</sub> = 25°C	-	3.3	-	μC
	Charge		T <sub>J</sub> = 175°C	_	12.5	_	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

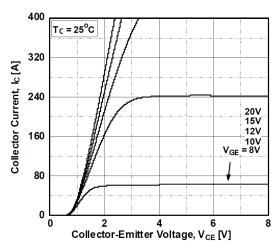


Figure 1. Typical Output Characteristics

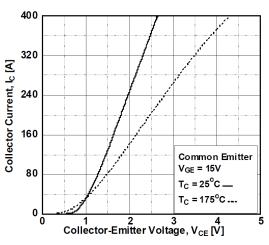


Figure 3. Typical Saturation Voltage Characteristics

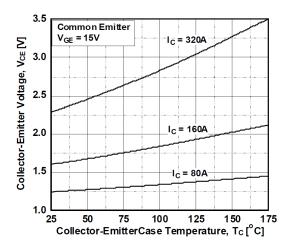


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

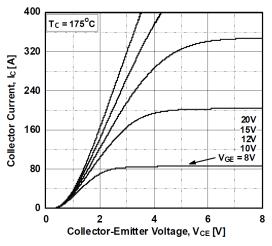


Figure 2. Typical Output Characteristics

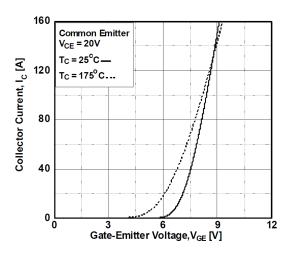


Figure 4. Transfer Characteristics

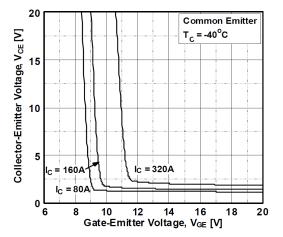


Figure 6. Saturation Voltage vs. V<sub>GE</sub>



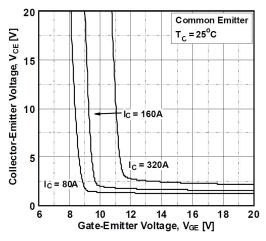


Figure 7. Saturation Voltage vs. V<sub>GE</sub>

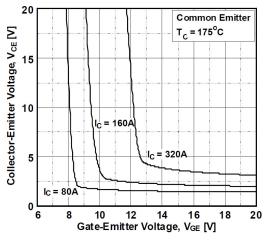


Figure 8. Saturation Voltage vs. V<sub>GE</sub>

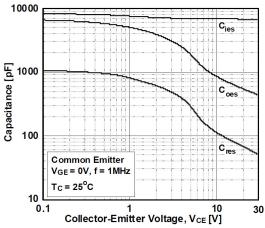


Figure 9. Capacitance Characteristics

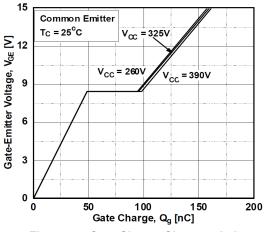


Figure 10. Gate Charge Characteristics

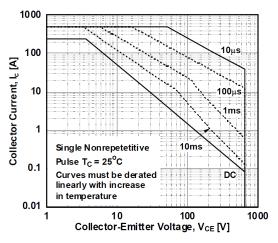


Figure 11. SOA Characteristics

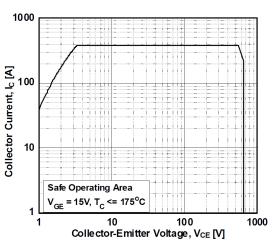


Figure 12. Turn Off Switching SOA Characteristics

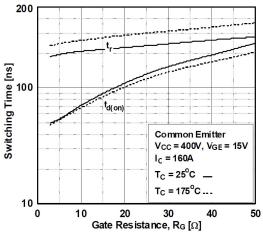


Figure 13. Turn-on Characteristics vs.

Gate Resistance

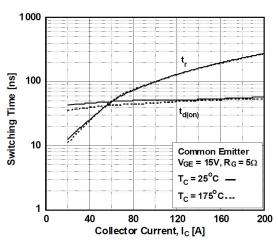


Figure 15. Turn-on Characteristics vs. Collector Current

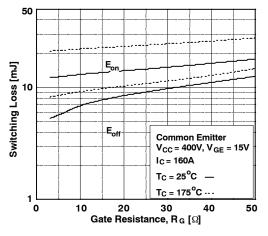


Figure 17. Switching Loss vs. Gate Resistance

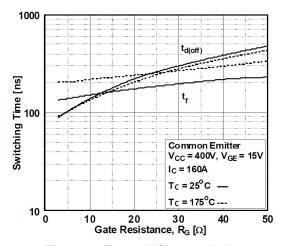


Figure 14. Turn-off Characteristics vs.

Gate Resistance

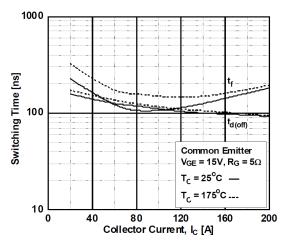


Figure 16. Turn-off Characteristics vs.
Collector Current

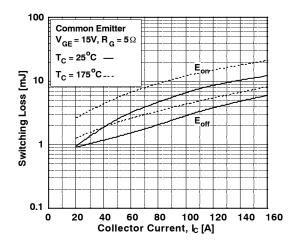


Figure 18. Switching Loss vs. Collector Current



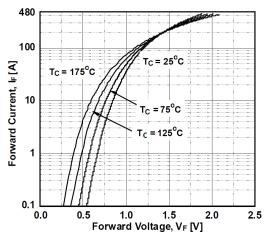


Figure 19. Forward Characteristics

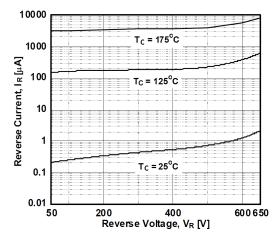


Figure 20. Reverse Current

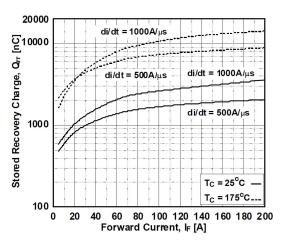


Figure 21. Stored Charge

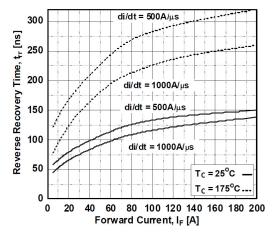


Figure 22. Reverse Recovery Time

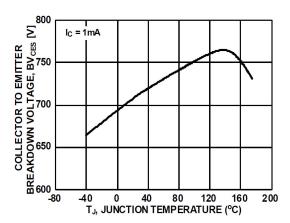


Figure 23. Collector to Emitter Breakdown Voltage vs. Junction Temperature

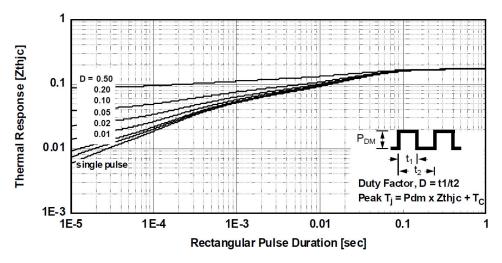


Figure 24. Transient Thermal Impedance of IGBT

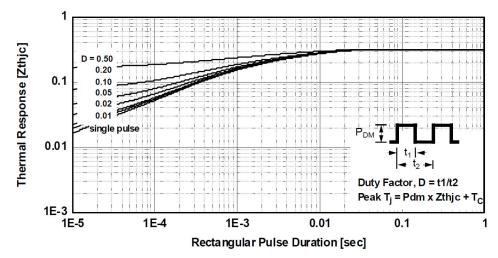
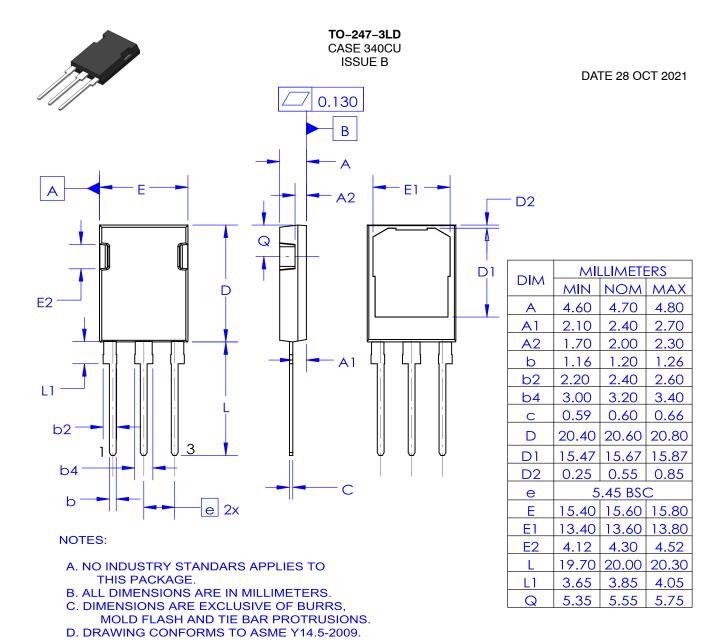


Figure 25. Transient Thermal Impedance of Diode





# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

A = Assembly Site Code

/ = Year

WW = Work Week

ZZ = Assembly Lot Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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